

Search Notes

Application/Control No.

10/821,169

Examiner

Hanh V. Tran

Applicant(s)/Patent under
Reexamination

SHIN ET AL.

Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
312	405 244	3/20/2006	HVT
	348.6		
16	413 436		
	444		
	Dig40		
16	Dig41	3/20/2006	HVT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search using various key words	3/20/2006	HVT